

PCN Number:	20190204004.1	PCN Date:	Feb 11, 2019
Title:	Qualification of RFAB as an additional Fab site option for select LBC7 devices		
Customer Contact:	PCN Manager	Dept:	Quality Services
Proposed 1st Ship Date:	May 11, 2019	Estimated Sample Availability:	Date provided at sample request.
Change Type:			
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process
<input type="checkbox"/>	Design	<input type="checkbox"/>	Assembly Materials
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Electrical Specification
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Mechanical Specification
<input checked="" type="checkbox"/>	Wafer Fab Site	<input checked="" type="checkbox"/>	Packing/Shipping/Labeling
		<input type="checkbox"/>	Test Process
		<input type="checkbox"/>	Wafer Bump Material
		<input type="checkbox"/>	Wafer Bump Process
		<input type="checkbox"/>	Wafer Fab Materials
		<input type="checkbox"/>	Wafer Fab Process
		<input type="checkbox"/>	Part number change

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of its RFAB fabrication facility as an additional Wafer Fab source for the selected devices listed in the "Product Affected" section.

Current Site			Additional Site		
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter
FFAB	LBC7	200 mm	RFAB	LBC7	300 mm

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current:

Current Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
FR-BIP-1	TID	DEU	Freising

Additional:

New Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
RFAB	RFB	USA	Richardson

Sample product shipping label (not actual product label)



MADE IN: Malaysia
2DC: 20:

MSL '2 / 260C / 1 YEAR	SEAL DT
MSL 1 / 235C / UNLIM	03/29/04

OPT:
ITEM: 39
LBL: 5A (L)T0:1750



(1P) SN74LS07NSR
(Q) 2000 (D) 0336
(31T) LOT: 3959047MLA
(4W) TKY (1T) 7523483S12
(P)
(2P) REV: (V) 0033317
(20L) CSO: SHE (21L) CCO:USA
(22L) ASO: MLA (23L) ACO: MYS

Product Affected:

TCA8418RTWR	TPS22913CYZVR	TPS22913CYZVT	
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Qualification Report

Approve Date 09-January-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TPS22913CYZVR	QBS Process Reference: TPS2543QRTE	QBS Package Reference: TPS63010YFF
AC	Autoclave, 2 atm, 121C	96 Hours	-	3/231/0	
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass
ELFR	Early Life Failure Rate, 125C	48 Hours	-	3/2400/0	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	3/231/0
HBM	ESD - HBM	2000 V	1/3/0	1/3/0	-
CDM	ESD - CDM	1000 V	1/3/0	1/3/0	-
HTOL	Life Test, 150C	300 Hours	-	3/231/0	3/231/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	3/231/0
HTSL	High Temp. Storage Bake, 175C	500 Hours	-	3/135/0	-
LU	Latch-up	(per JESD78)	1/6/0	1/6/0	-
TC	Temperature Cycle, -55/150C	700 Cycles	-	-	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0	-
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	-	3/231/0

- QBS: Qual By Similarity

- Qual Device TPS22913CYZVR is qualified at LEVEL 1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Qualification Report

Approve Date 23-January-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TCA8418RTWR	QBS Process Reference: TPS2543QRTE	QBS Package Reference: THS4552IRTW
AC	Autoclave, 2 atm, 121C	96 Hours	-	3/231/0	
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass
ELFR	Early Life Failure Rate, 125C	48 Hours	-	3/2400/0	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	3/231/0
HBM	ESD - HBM	2000 V	1/3/0	1/3/0	-
CDM	ESD - CDM	1000 V	1/3/0	1/3/0	-
HTOL	Life Test, 150C	300 Hours	-	3/231/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	3/231/0
HTSL	High Temp. Storage Bake, 175C	500 Hours	-	3/135/0	-
LU	Latch-up	(per JESD78)	1/6/0	1/6/0	-
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0	3/231/0
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	-	3/231/0

- QBS: Qual By Similarity

- Qual Device TCA8418RTWR is qualified at LEVEL 2-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
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